



$V_{DSS}$           60V

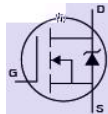
$R_{DS(on)}$     11.5m

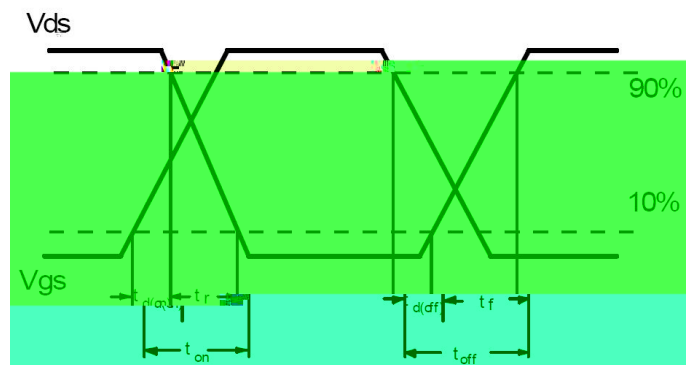
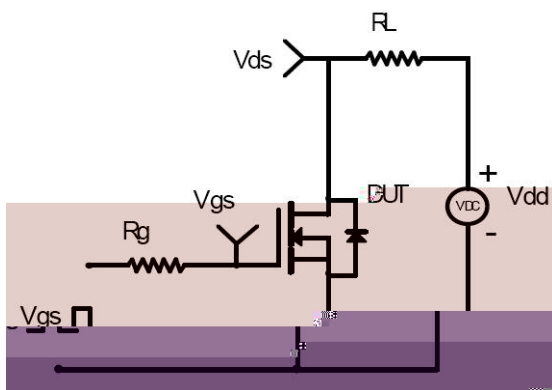
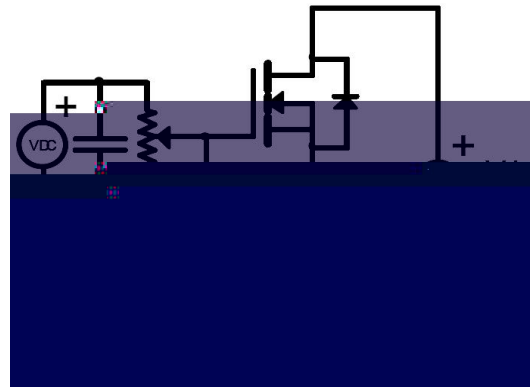
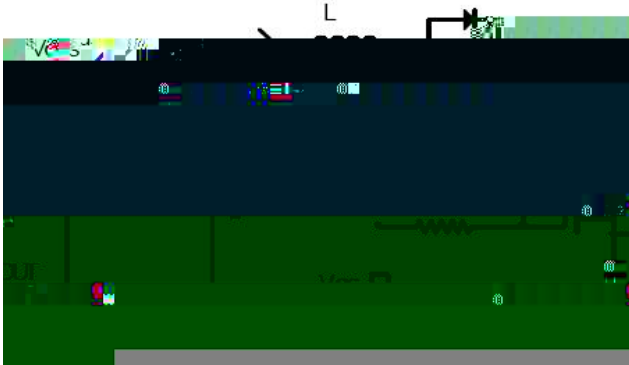
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	50	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	30	
$I_{DM}$	Pulsed Drain Current	200	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation	65	W
$V_{DS}$	Drain-Source Voltage	60	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

$R_{JC}$	Junction-to-case	—	1.9	/W
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@ $T_A=25$  unless otherwise specified

$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	60	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	11.5	15	m	$V_{GS}=10V, I_D = 20A$
$V_{GS(th)}$	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu A$	$V_{DS} = 60V, V_{GS} = 0V$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20V$
		—	—	-100		$V_{GS} = -20V$
$C_{iss}$	Input capacitance	—	1722	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output capacitance	—	125	—		$V_{DS} = 25V$
$C_{rss}$	Reverse transfer capacitance	—	108	—		$f = 1MHz$
$Q_g$	Total gate charge	—	37	—	nC	$I_D = 30A,$
$Q_{gs}$	Gate-to-Source charge	—	6	—		$V_{DS}=30V,$
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	10	—		$V_{GS} = 10V$
$t_{d(on)}$	Turn-on delay time	—	15	—	ns	$V_{GS}=10V, V_{DS} = 30V,$ $R_{GEN}=1.8, I_D = 30A$
$t_r$	Rise time	—	10	—		
$t_{d(off)}$	Turn-Off delay time	—	36	—		
$t_f$	Fall time	—	29	—		

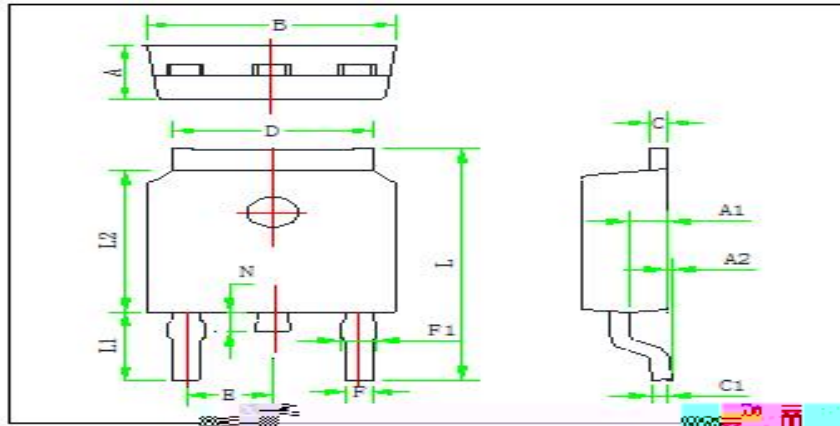
$I_S$	Continuous Source Current (Body Diode)	—	—	50	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	200	A	
$V_{SD}$	Diode Forward Voltage	—	—	1.2	V	$I_S=30A, V_{GS}=0V$
$t_{rr}$	Reverse Recovery Time	—	38	—	ns	$T_J = 25^\circ C, I_F = 30A, di/dt =$
$Q_{rr}$	Reverse Recovery Charge	—	50	—	nC	100A/ $\mu s$



Calculated continuous current based on maximum allowable junction temperature.

Repetitive rating; pulse width limited by max. junction temperature.

The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.



C1	0.43	0.50	0.58
D	5.12	5.32	5.52
E		2.286 TYP	
F	0.66	0.76	0.86
F1	0.66	0.86	1.06
L	9.60	9.90	10.20
L1	2.6	2.8	3.0
L2	5.95	6.10	6.25
N	0.60	0.80	1.00



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